

Notice of References Cited

Application/Control No.

10/722,776

Applicant(s)/Patent Under
Reexamination
WANG ET AL.

Examiner

NANCY BITAR

Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,065,230	06-2006	Yuasa et al.	382/104
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.